

EAST Search History

Re f #	Hits	Search Query	DBs	Defau lt Oper ator	Plur als	Time Stamp
L1 0	5	("symbol node" SAME "check node" SAME "bit node").clm.	US-PGP UB	AND	ON	2006/08/29 08:33

Interference Search

EAST Search History

Re f #	Hits	Search Query	DBs	Defau lt Oper ator	Plur als	Time Stamp
L2	1069	(714/752 or 714/791 or 714/794).ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:49
L3	877	(H03M013/11 or H03M013/13 or H03M013/39).ipc.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:49
L4	20	(LDPC or "low density parity check") and "modulation encoding"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:49

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L5	218	("low density parity check") and constellation	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 07:33
L6	212	(LDPC) and constellation	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:49
L7	37	("low density parity check") and "symbol node"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:50

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L8	36	LDPC and "symbol node"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/08/29 06:50
L9	1	"20040255228"	US-PGP UB	AND	ON	2006/08/29 07:25

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Tue, 29 Aug 2006, 8:10:43 AM EST

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- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

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Recent Search Queries

Results

#1	((low density parity check<in>metadata) <and> (symbol node<in>metadata))	9
#2	((ldpc<in>metadata) <and> (symbol node<in>metadata))	10

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